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(54) **PROBE ACCESSORIES, AND METHODS FOR PROBING TEST POINTS USING SAME**

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See application file for complete search history.

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(57) **ABSTRACT**

Probe accessories, and methods for routing signals between a target and a test instrument using the probe accessories, are disclosed. Some of the probe accessories include a flexible circuit and first and second pairs of contacts. Flexible circuit design varies, but one embodiment has first and second regions, a first conductor and a second conductor, and a separation feature. The first conductor extends into the first region while the second conductor extends into both the first and second regions and has a fixed spacing with respect to the first conductor. A separation feature extends between first and second regions and is operable to create two independently maneuverable legs, each leg comprising an end portion of the first and second regions, while maintaining a fixed spacing between the first and second conductors. The first and second pairs of contacts electrically couple the probe accessories between test points and test instruments.

19 Claims, 8 Drawing Sheets

